

# Physical Property Improvement of Atomic Layer Deposited Thin-film Interconnects

Ajit R. Dhamdhere<sup>1\*</sup>, Ben Nie<sup>1</sup>, Hyun Chol Cho<sup>1</sup>, Hae Young Kim<sup>1</sup>

Affiliations: <sup>1</sup>Eugenus, Inc., 677 River Oaks Parkway, San Jose, CA, USA, 95134

\* Contact email: [a.dhamdhere@eugenustech.com](mailto:a.dhamdhere@eugenustech.com)

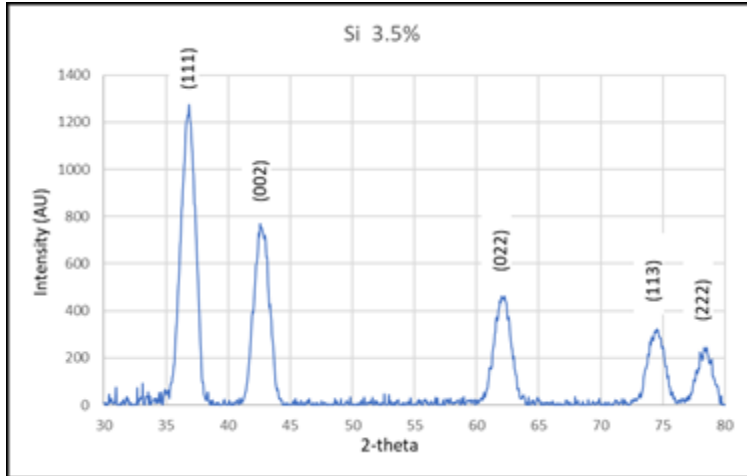


Figure 1

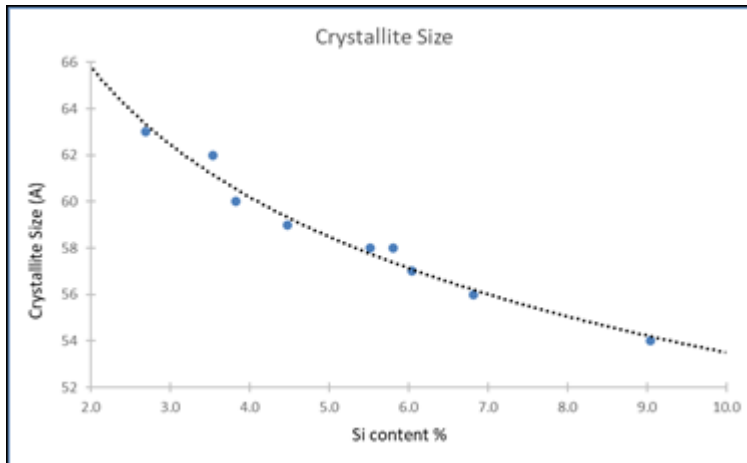


Figure 2

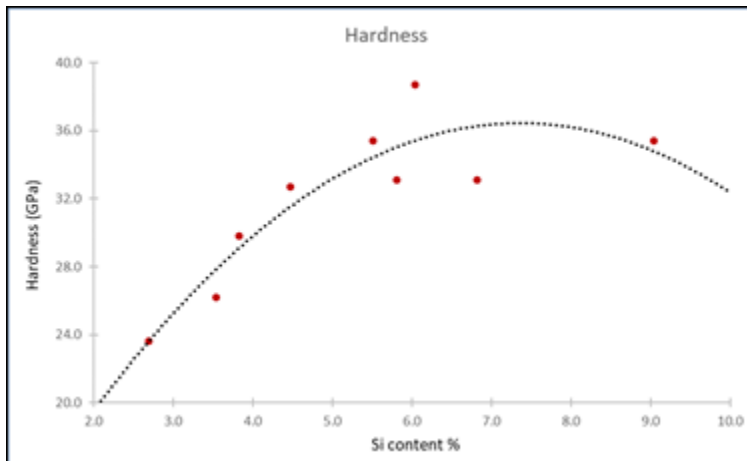


Figure 3

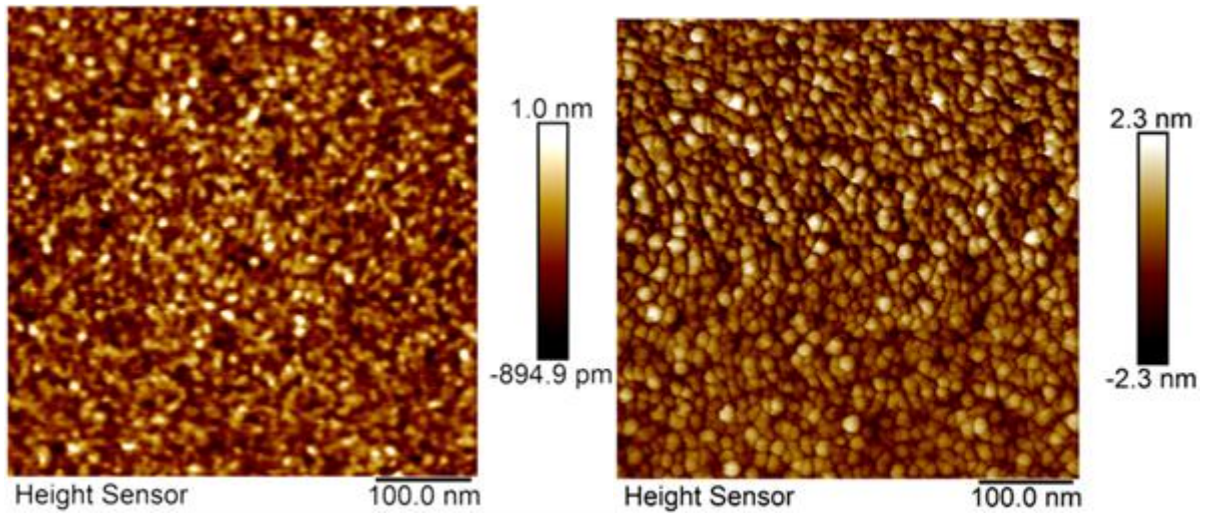


Figure 4

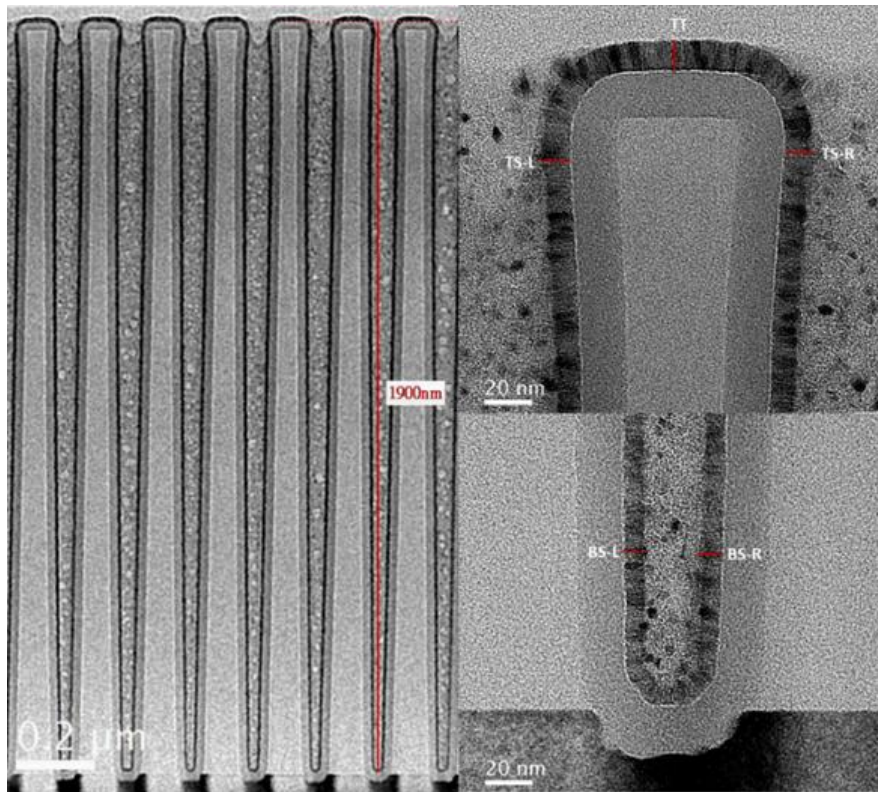


Figure 5